## Application/Control No. O9/435,748 Reexamination BUCKLEY ET AL. Examiner Mark Ruthkosky Applicant(s)/Patent Under Reexamination BUCKLEY ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6165642	12-2000	Kawakami	429/218.1
	В	US-6033805	03-2000	Dansui	429/223
-	С	US-5571638	11-1996	Satoh	429/248
*	D	US-6475663	11-2002	Muhwald	429/129
*	Е	US-6391494	05-2002	Reitz	429/219
*	F	US-6344271	02-2002	Yadav	428/402
*	G	US-6203947	03-2001	Peled	429/231.95
*	Н	US-6194099	02-2001	Gernov	429/213
*	ı	US-5965296	10-1999	Nishimura	429/231.8
*	J	US-5952125	09-1999	Bi	429/231.2
*	К	US-5900335	05-1999	Nishimura	429/231.4
*	L	US-5879836	03-1999	Ikeda	429/231.8
	М	US-6037095	03-2000	Miyasaka	429/218.1

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 855 752	07-1998	EPO	Kawakami	H01M 4/02
	0	/				
	Р					
	Q					
	R					
	S				·	
	Т					

## **NON-PATENT DOCUMENTS**

\* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

U

W

X

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.